

In place of PTO-1449 Form	U. S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Complete if Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> (use as many sheets as necessary)		JAN 15 2005 U.S. PATENT AND TRADEMARK OFFICE		
SHEET	1	OF	2	Application Number: 10/684,120 Filing Date: 10/10/2003 Applicant(s): Christof Baur, et al. Priority Number: 2881 Examiner/Name: Jack I. Berman Attorney/Docket Number: 34003.55

U. S. PATENT DOCUMENTS				
Examiner's Initials	Cite No.	Document Number	Publication Date	Name of Patentee or Applicant of Cited Document
JB	A1	5,144,148	09/01/1992	Donald M. Eigler

OTHER PRIOR ART				
Examiner's Initials	Cite No.	Include name of the author (in CAPITAL LETTERS); title of the article; title of the item; date; page(s); volume; issue number(s); publisher; city/country where published.		
JB	A2	M.T. CUBERES, R.R. SCHLITTLER, J.K. GIMZEWSKI; <i>Manipulation of C<sub>60</sub> molecules on Cu(111) surfaces using a scanning tunneling microscope</i> ; Appl. Phys. A 66, S669-S673 (1998)		
JB	A3	J.T. LI, W.D. SCHNEIDER, R. BERNDT; <i>Low-temperature manipulation of Ag atoms and clusters on a Ag (110) surface</i> ; Appl. Phys. A 66, S675-S678 (1998)		
JB	A4	M.T. CUBERES, R.R. SCHLITTLER, J.K. GIMZEWSKI; <i>Supramolecular assembly of individual C<sub>60</sub> molecules on a monolayer of 4, 4'-dimethylbianthrone molecules</i> ; Appl. Phys. A 66, S745-S748 (1998)		
JB	A5	T. SHIMIZU, J.T. KIM, H. TOKUMOTO; <i>Tungsten silicide formation on an STM tip during atom manipulation</i> ; Appl. Phys. A 66, S771-S775 (1998)		
JB	A6	G. MEYER, L. BARTELS, S. ZÖPHEL, K.H. RIEDER; <i>Lateral manipulation of adatoms and native substrate atoms with the low-temperature scanning tunneling microscope</i> ; Appl. Phys. A 68, 125-129 (1999)		
JB	A7	X. HU, P. VON BLANCKENHAGEN; <i>Nano-scale metal cluster deposition using STM</i> ; Appl. Phys. A 68, 137-143 (1999)		
JB	A8	A.A.G. REQUICHA, S. MELTZER, R. RESCH, D. LEWIS, B.E. KOEL, M.E. THOMPSON; <i>Layered nanoassembly of three-dimensional structures</i> ; Laboratory for Molecular Robotics, University of Southern California		
JB	A9	J.W. LYDING, G.C. ABEIN, T.C. SHEN, C. WANG, J.R. TUCKER; <i>Nanometer scale patterning and oxidation of silicon surfaces with an ultrahigh vacuum scanning tunneling microscope</i> ; J. Vac. Sci. Technol. B 12(6), Nov/Dec 1994, pp. 3735-3740		
JB	A10	G.C. ABEIN, M.C. HERSAM, D.S. THOMPSON, S.T. HWANG, H. CHOI, J.S. MOORE, AND J.W. LYDING; <i>Approaches to nanofabrication on Si(100) surfaces: Selective area chemical vapor deposition of metals and selective chemisorption of organic molecules</i> ; J. Vac. Sci. Technol. B 16(6), Nov/Dec 1998, pp. 3874-3878		
JB	A11	R. RESCH, C. BAUR, A. BUGACOV, B.E. KOEL, A. MADHUKAR, A.A.G. REQUICHA, P. WILL; <i>Building and manipulating three-dimensional and linked two-dimensional structures of nanoparticles using scanning force microscopy</i> ; Langmuir The ACS Journal of Surfaces and Colloids, November 10, 1998, Vol. 14, No. 23		
JB	A12	J.S. FOSTER, J.E. FROMMER, P.C. ARNETT; <i>Molecular manipulation using a tunneling microscope</i> ; IBM Research Division, Almaden Research Center, San Jose, California; Nature Vol. 331, January 28, 1988, pp. 324-326		
JB	A13	G. DUJARDIN, A. MAYNE, O. ROBERT, F. ROSE, C. JOACHIM, H. TANG; <i>Vertical manipulation of individual atoms by a direct STM tip-surface contact on Ge(111)</i> ; Physical Review Letters, Vol. 80, No. 14, April 6, 1998, pp. 3085-3088		

Examiner Signature	Jack Berman	Date Considered	4/4/2005
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

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SHEET	2	OF	2	
		<b>Application Number:</b> 10/684,120 <b>Filing Date:</b> October 10, 2003 <b>Applicant(s):</b> Christof Baur, et al. <b>Art. Unit:</b> 2881 <b>Examiner Name:</b> Jack I. Berman <b>Attorney/Docket Number:</b> 34003.55		

Examiner Signature	<i>Jaip Berman</i>	Date Considered	4/4/2005
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